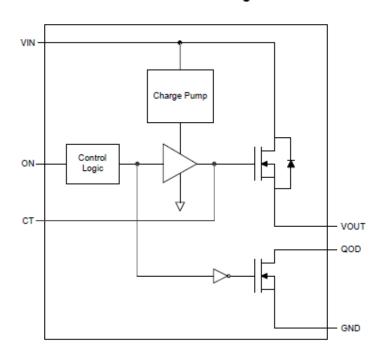


Functional Safety FIT Rate, Failure Mode Distribution TPS22918-Q1

5.5-V, 2-A, 52-m Ω On-Resistance Load Switch

Functional Block Diagram



| Failure Rate Mission Profile (1) | Per 10 ⁹ Hours (FIT) |
|----------------------------------|---------------------------------|
| Total FIT Rate | 6 |
| Die FIT Rate | 4 |
| Package FIT Rate | 2 |

| FIT Siemens | Norm SN29500 (2) | | |
|-------------|------------------------|-------------------------|-----------------------------------|
| Table | Category | Ref FIT λ_{ref} | Ref Virtual Tj $\theta_{v_{j,1}}$ |
| | | | |
| Table 5 | Digital, Analog, Mixed | 20 FIT | 55 C |

| Failure Modes | Failure Mode Distribution (%) |
|---|-------------------------------|
| VOUT open (HiZ) | 25 |
| VOUT stuck on (VIN) | 15 |
| VOUT functional, not in specification voltage or timing | 45 |
| QOD stuck off | 5 |
| QOD stuck on | 5 |
| Pin to Pin short any two pins | 5 |

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(1) Failure Rate, Mission Profile and Failure Modes Distribution

The failure rate and mission profile information come from reliability modeling for Integrated circuits in Reliability

data handbook IEC TR 62380 and ISO 26262 Part 11

Mission Profile: Motor Control from Table 11 Power dissipation 150 mW

Climate type: World-wide Table 8 Package factor lambda 3 Table 17b

Substrate Material: FR4 EOS FIT rate assumed = 0

(2) Reference failure rate, Virtual (equivalent) junction temperature

The reference failure rate and virtual junction temperature come from Siemens Norm SN29500-2 tables 1-5. Failure rate for user mission profile is calculated using the reference failure rate and virtual junction temperature and following the calculation information in SN29500-2 section 4.

The failure mode distribution estimation comes from the combination of common failure modes listed in standards such as IEC 61508 and ISO 26262, the ratio of sub-circuit function size and complexity and from best engineering judgment. The failure rates listed reflect random failure events and do not include failures due to misuse or over stress.

TPS22918-Q1 is a catalog product and not compliant to ISO-26262 standards.

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